

**Notice of References Cited**

Application/Control No.

10/581,578

Applicant(s)/Patent Under  
Reexamination  
HAYASHI ET AL.

Examiner

Brian Walck

Art Unit

1793

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**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2003/0179537 A1	09-2003	Tanaka et al.	361/502
	B	US-			
	C	US-			
	D	US-			
	E	US-			
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N	EP 1103523 A2	05-2001	European Patent	IWASAKI et al.	C01B 31/08
	O					
	P					
	Q					
	R					
	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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	V	
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